

IEC QUALITY ASSESSMENT SYSTEM (IECQ) covering Electronic Components,

Assemblies, Related Materials and Processes For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 17.0001

CB Certificate No.: 50600164 ITL

Schedule Number: IECQ-L ULTW 17.0001-S Rev No.: 2 Revision Date: 2022/03/31 Page 1 of 2

Appendix-1 (50600164 ITL) Schedule of Scope to Certificate of Approval

Test Items	Standard/Method
I-V Probe station	WI-LQ-0120 Probe station Work Instruction
InGaAs microscope/Optical Beam Induced Resistance Change (OBIRCH)	WI-LQ-0313 Meridian Work Instruction
SAT (Scanning Acoustic Tomography)	WI-LQ-0320 SAT Work Instruction
3D X-ray	WI-LQ-0324 3D X-ray Work Instruction
Secondary Electron Microscope (SEM)	WI-LQ-0302 SEM Work Instruction
Focused Ion Beam (FIB)	WI-LQ-0108 FIB Work Instruction
Electrostatic Discharge (ESD) / Latch-up (Heating by Thermo stream)	HBM: ANSI/ESDA/JEDEC JS-001/JESD22-A114 / AEC-Q100-002 / MIL-STD-883 MM: JED22-A115 / AEC-Q100-003 CDM: ANSI/ESDA/JEDEC JS-002 / JESD22-C101 / AEC-Q100-011 Latch : JESD78 / AEC-Q100-004
High Temperature Operating Life (HTOL)	JESD22-A108
Bias Life Test (BLT)	JESD22-A108
Early Failure Rate (EFR)	JESD22-A108
High Temperature Storage Life (HTSL)	JESD22-A103
Low Temperature Storage Life (LTSL)	JESD22-A108
Highly Accelerated Temperature And Humidity Stress Test (HAST)	JESD22-A110
Unbiased HAST	JESD22-A118
Pressure Cook Test (PCT)	JESD22-A102

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DQS-Group - DQS Taiwan Inc., Feng Yuan Dist., Taichung City, Taiwan

IECQ-P Schedule of Scope Rev. 01



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Temperature Cycling Test (TCT)	JESD22-A104
Thermal Shock Test (TST)	JESD22-A106
Precondition	IPC/JEDEC J-STD-020D Level 3, JESD22-A113
Steady State Temperature Humidity Bias Life Test (THB)	JESD22-A101

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Technical Reviewer of DQS:

Date: 3/31/2022

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